

PATENT ASSIGNMENT

Electronic Version v1.1

Stylesheet Version v1.1

SUBMISSION TYPE:

NEW ASSIGNMENT

NATURE OF CONVEYANCE:

CHANGE OF NAME

CONVEYING PARTY DATA

Name	Execution Date
Molecular Imaging Corp	01/04/2006

RECEIVING PARTY DATA

Name:	Agilent Technologies, Inc.
Street Address:	815 SW 14th Street
Internal Address:	Attn: Sue Hebert DM 525
City:	Loveland
State/Country:	COLORADO
Postal Code:	80537

Name:	Molecular Imaging Corp, a wholly owned subsidiary of Agilent Technologies, Inc.
Street Address:	815 S. W. 14th Street
Internal Address:	Intellectual Property Administration, DM286 Post J5
City:	Loveland
State/Country:	OHIO
Postal Code:	80537-0599

PROPERTY NUMBERS Total: 33

Property Type	Number
Patent Number:	5440920
Patent Number:	5587523
Patent Number:	5763767
Patent Number:	5155361
Patent Number:	RE35317
Patent Number:	5750989
Patent Number:	5495109
Patent Number:	5621210

PATENT

500097652

REEL: 017519 FRAME: 0904

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Patent Number:	5760396
Patent Number:	5805448
Patent Number:	5630932
Patent Number:	6017590
Patent Number:	5515719
Patent Number:	5612491
Patent Number:	5513518
Patent Number:	5866805
Patent Number:	5753814
Patent Number:	5983712
Patent Number:	6134955
Patent Number:	5654546
Patent Number:	5821545
Patent Number:	4868396
Patent Number:	5500535
Patent Number:	6121611
Patent Number:	6051825
Patent Number:	6245204
Patent Number:	6734438
Patent Number:	6748795
Patent Number:	6952952
Application Number:	11152827
Application Number:	10725769
Application Number:	60650285
Patent Number:	5675154

# CORRESPONDENCE DATA

Fax Number: (970)635-6836  
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Phone: 970 679-3185  
Email: Sue\_hebert@agilent.com  
Correspondent Name: Agilent Technologies, Inc.  
Address Line 1: 815 SW 14th Street  
Address Line 2: Attn: Sue Hebert DM 525  
Address Line 4: Loveland, COLORADO 80537

NAME OF SUBMITTER:	Sue A. Hebert
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**Total Attachments: 6**

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**PATENT**

**REEL: 017519 FRAME: 0906**

## ASSIGNMENT

THIS AGREEMENT (this "Agreement") is entered into as of 1-4-2006 (the "Effective Date") by and between Agilent Technologies, Inc., ("Agilent"), organized under the laws of the State of Delaware and Molecular Imaging Corp., ("MI"), organized under the laws of the State of Arizona. Agilent and MI are hereinafter referred to as the "Parties."

WHEREAS, the Parties have entered into an Agreement and Plan of Merger effective as of November 29, 2005 under which MI became a wholly-owned subsidiary of Agilent (the "Merger Agreement");

WHEREAS, Agilent has decided to cause the transfer the assets of its wholly-owned subsidiary, MI to Agilent and then to liquidate the MI shell corporation.

NOW, THEREFORE, for and in consideration of the mutual covenants contained in the Merger Agreement, the share purchase price paid by Agilent under the Merger Agreement and for other good and valuable consideration receipt of which each party hereby acknowledges, the parties hereby agree as follows:

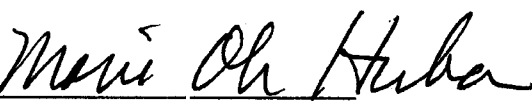
1. GRANT OF RIGHTS. MI agrees to assign all of MI's right, title and interest in its inventions, including without limitation, inventions not yet the subject of patents or patent applications, the patents and the patent applications listed in Exhibit A, including, without limitation, domestic and foreign rights thereto, the right to file domestic and foreign patent applications thereon, and its rights in any and all patents that issue therefrom.
2. AMENDMENT. This Agreement shall not be amended or otherwise modified except by a written agreement dated subsequent to the date of this Agreement and signed on behalf of MI and Agilent by their respective duly authorized representatives.
3. GOVERNING LAW. This Agreement shall be governed by and construed in accordance with the laws of the State of California.
4. ASSIGNMENT. This Agreement shall be binding upon and inure to the benefit of the parties hereto and their respective successors and assigns.

IN WITNESS WHEREOF, the parties have executed this Agreement as of the Effective Date.

Molecular Imaging Corp.

By:   
its authorized representative

Agilent Technologies, Inc.

By:   
its authorized representative

# EXHIBIT A

Country	Title	Pat. or App. No.	Status Remarks
US	Novel stationary-sample stage atomic force microscope with beam-tracking lens and s-shaped scanner	5,440,920	Issued
US	Atomic force microscope employing beam-tracking	5,587,523	Issued Continuation of 5,440,920
US	Atomic force microscope employing beam-tracking	5,763,767	Issued Continuation of 5,587,523
US	Potentiostatic preparation of molecular adsorbates for scanning probe microscopy	5,155,361	Issued
US	Potentiostatic preparation of molecular adsorbates for scanning probe microscopy	RE 35,317	Issued Reissue of 5,155,361
US	Scanning probe microscope for use in fluids	5,750,989	Issued
US	Electrochemical identification of molecules in a scanning probe microscope	5,495,109	Issued CIP of 5,750,989
US	Microscope for force and tunneling microscopy in liquids	5,621,210	Issued CIP of 5,750,989
US	Scanning probe microscope	5,675,154	Issued CIP of 5,750,989

US	Scanning probe microscope for use in fluids	5,760,396	Issued Divisional of 5,675,154
US	Hybrid control system for scanning probe microscope	5,805,448	Issued FWC of 08/403,229
US	Tip etching system and method for etching platinum-containing wire	5,630,932	Issued
US	Tips and substrates for scanning probe microscopy	6,017,590	Issued Divisional of 5,630,932
US	Controlled force microscope for operation in liquids	5,515,719	Issued
US	Formation of a magnetic film on an atomic force microscope cantilever	5,612,491	Issued Divisional of 5,513,518
US	Modulation of force sensor for ac detection in an atomic force microscope	5,513,518	Issued CIP of 5,515,719
US	Cantilevers for magnetically driven atomic force microscope	5,866,805	Issued CIP of 5,612,491
US	Magnetically-oscillated probe microscope for operation in liquids	5,753,814	Issued CIP of 5,866,805
US	Magnetic modulation of force sensor for ac detection in an atomic force microscope	5,983,712	Issued CIP of 5,866,805
US	Magnetic modulation of force sensor for ac detection in an atomic force microscope	6,134,955	Issued CIP of 5,866,805
US	Variable temperature scanning probe microscope based on a peltier device	5,654,546	Issued

US	Heated stage for a scanning probe microscope	5,821,545	Issued CIP of 5,654,546
US	Cell and substrate for electrochemical STM studies	4,868,396	Issued
US	Stress cell for a scanning probe microscope	5,500,535	Issued
US	Force sensing probe for scanning probe microscopy	6,121,611	Issued
US	Conducting scanning probe microscope with environmental control	6,051,825	Issued
US	Vibrating tip conducting probe microscope	6,245,204	Issued
US	Scanning probe microscope and solenoid driven cantilever assembly	6,734,438	Issued
US	Pendulum scanner for scanning probe microscope	6,748,795	Issued
US	Topography and recognition imaging atomic force microscope and method of operation	6,952,952	Issued
US	Topography and recognition imaging atomic force microscope and method of operation	U.S. Ser. No. 11/152,827	Pending

US	Fast scanning stage for a scanning probe microscope	U.S. Ser. No. 10/725,769 (Publication No. 2004-0129873)	Published
US	Cross-linking compositions for use in atomic force microscopy	Provisional U.S. Ser. No. 60/650,285	Pending
JP	Scanning probe microscope for use in fluids	JP3249130	Issued
JP	Magnetic modulation of force sensor for ac detection in an atomic force microscope	JP3249132	Issued
JP	Force sensing probe for scanning probe microscopy	JP2000-549903	Published
JP	Microscope for compliance measurement	JP2000-505482	Published
JP	Fast scanning stage for a scanning probe microscope	JP2005-509973	Pending
GB	Microscope for compliance measurement	EP1002216	Issued
GB	Magnetic modulation of force sensor for ac detection in an atomic force microscope	EP0813675	Issued
GB	Force sensing cantilever for atomic force microscope	EP1080340	Issued
GB	Fast scanning stage for a scanning probe microscope	GB2415042	Published
GB	Topography and recognition imaging atomic force microscope and method of operation	GB2414547	Pending
Germany	Microscope for compliance measurement	EP1002216	Issued



Germany	Magnetic modulation of force sensor for ac detection in an atomic force microscope	EP0813675	Issued
Germany	Force sensing probe for scanning probe microscopy	EP1080340	Issued
Germany	Topography and recognition imaging atomic force microscope and method of operation	DE10393612	Published
Germany	Fast scanning stage for a scanning probe microscope	DE10393939	Pending
France	Force sensing probe for scanning probe microscopy	EP1080340	Issued
WO	Fast scanning stage for a scanning probe microscope	WO2004-059243	Entered
WO	Topography and recognition imaging atomic force microscope and method of operation	WO2004-042741	Entered